

Pseudo-cubic crystal structure and phase transition in doped ye'elimit

Ana Cuesta[†], Ángeles G. De la Torre[†], Enrique R. Losilla[†], Isabel Santacruz[†], Miguel A. G. Aranda*[†]#

[†] Departamento de Química Inorgánica, Cristalografía y Mineralogía, Universidad de Málaga, 29071-Málaga, Spain.

ALBA Synchrotron, Carretera BP 1413, Km. 3.3, E-08290 Cerdanyola, Barcelona, Spain

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Table S1: Final (refined) atomic parameters (coordinates and anisotropic displacement parameters) for doped ye'elimit at room temperature.

Atom	Ca1	Al1	S1*	O1	O2*
Wyckoff position	8c	12d	2a	24g	24g
occupation factor	1	1	1	1	0.3333
x	0.2944(1)	0.2500	0.0000	0.3479(2)	0.1129(5)
y	0.2944 (1)	0.5000	0.0000	0.3479(2)	0.1129(5)
z	0.2944 (1)	0.0000	0.0000	0.0533(3)	0.0136(16)
u₁₁	0.096(1)	0.007(1)	0.087(2)	0.028(1)	0.139(7)
u₂₂	0.096(1)	0.015(1)		0.028(1)	
u₃₃	0.096(1)	0.015(1)		0.034(2)	
u₁₂	0.069(2)	0.000		0.009(1)	
u₁₃	0.069(2)	0.000		0.007(1)	
u₂₃	0.069(2)	0.000		0.007(1)	

*isotropic displacement parameters

Table S2: Selected interatomic distances (Å) and angles (°) for doped ye'elimit at room temperature.

Ca-O	
Ca(1)-O(1)x3	2.324(3)
Ca(1)-O(1)x3	3.016(2)
Ca(1)-O(2)x3	2.350(14)
Al-O	
Al(1)-O(1) x4	1.734(1)
O(1)-Al(1)-O(1) x2	117.4 (2)
O(1)-Al(1)-O(1) x4	105.6(7)
S-O	
S(1)-O(2) x4	1.474(6)

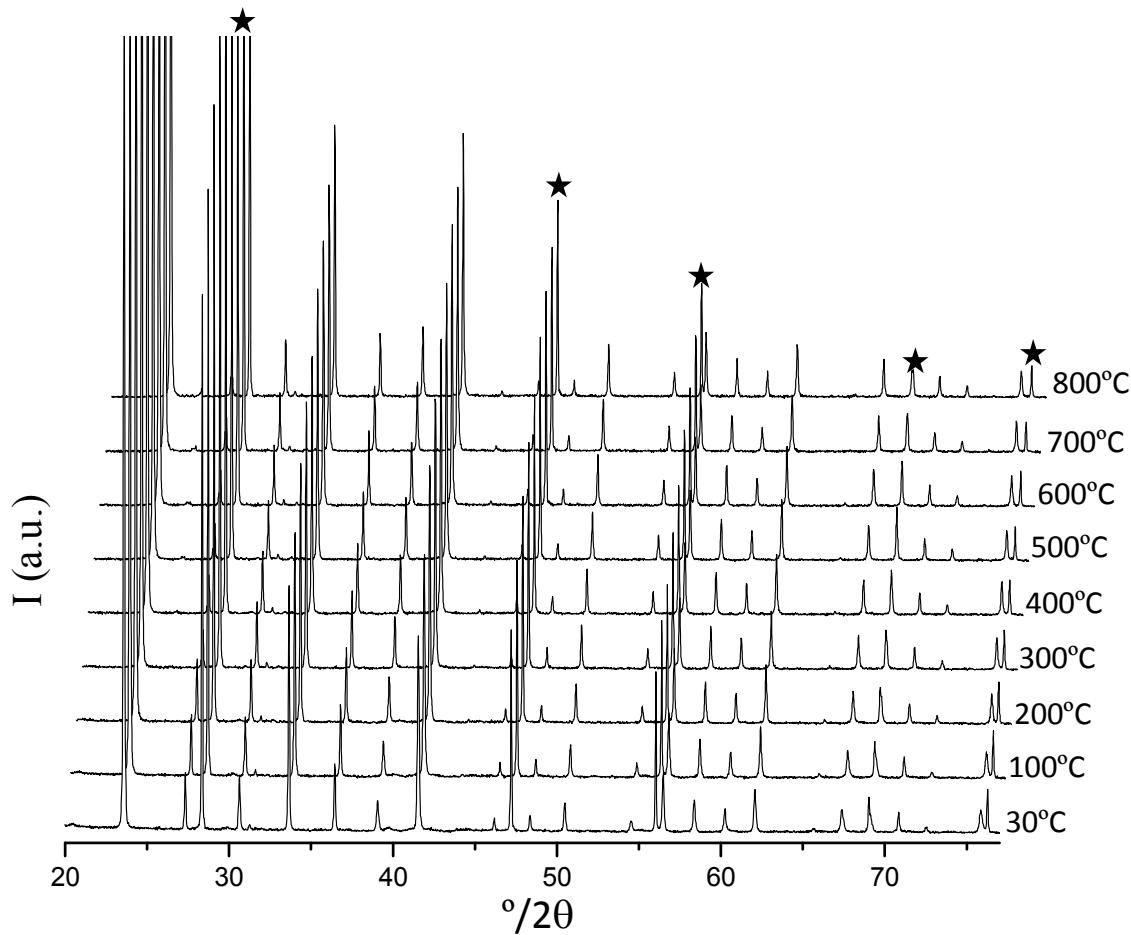


Figure S1: Full thermodiffractometric study for doped ye'elimit with Si added as internal standard (starred peaks are those coming from the added standard).

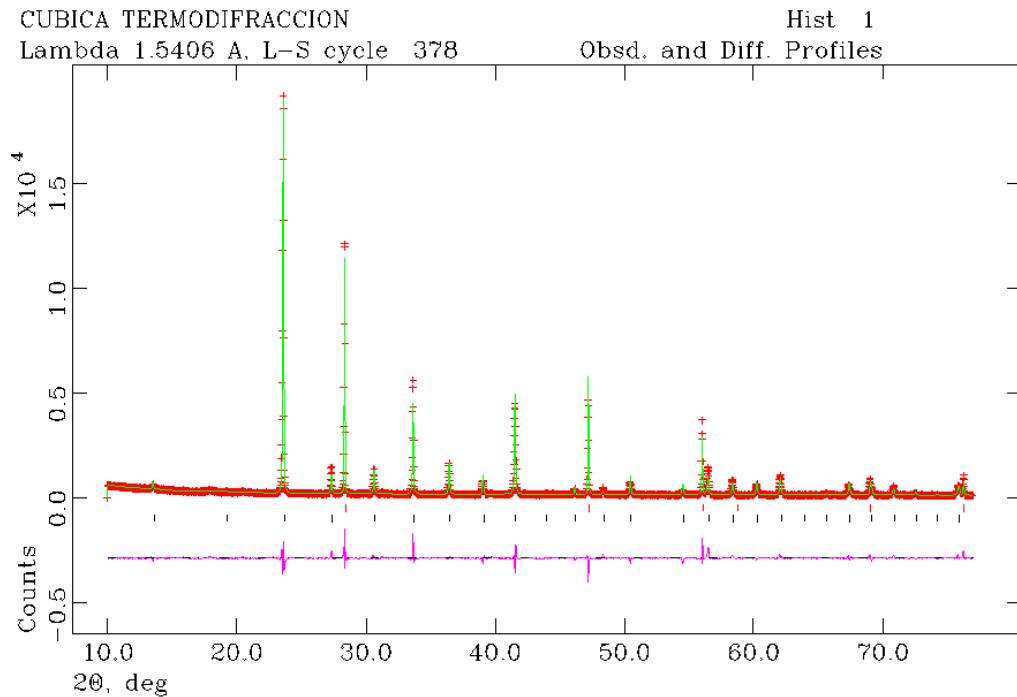


Figure S2. Laboratory X-ray powder diffraction Rietveld plot for doped ye'elimit mixed with silicon (internal standard) at 30 °C.

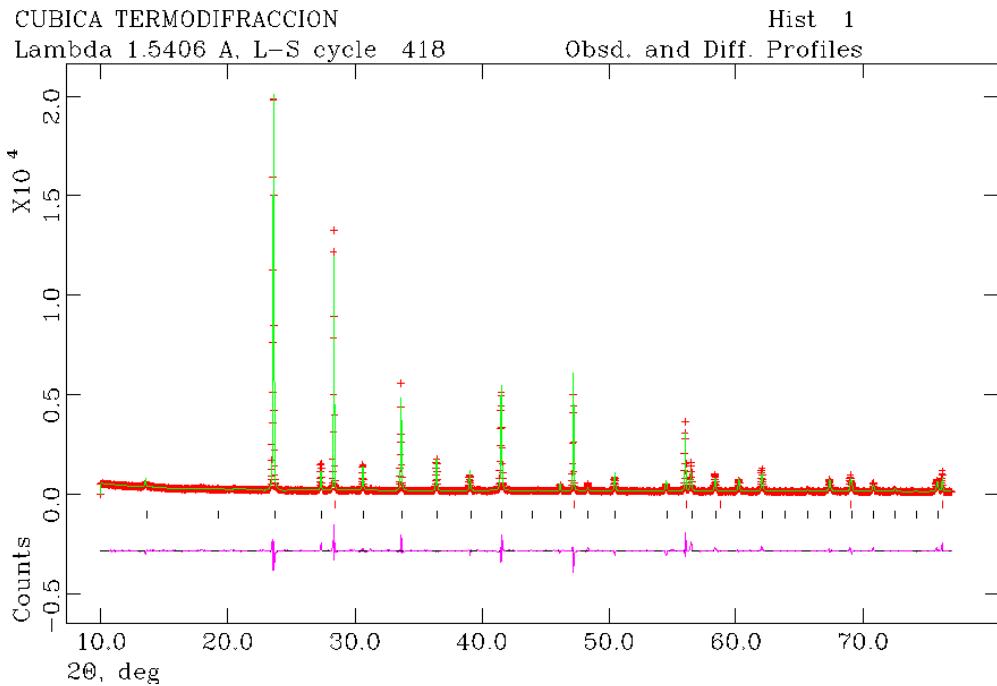


Figure S3. Laboratory X-ray powder diffraction Rietveld plot for doped ye'elimit mixed with silicon (internal standard) at 100 °C.

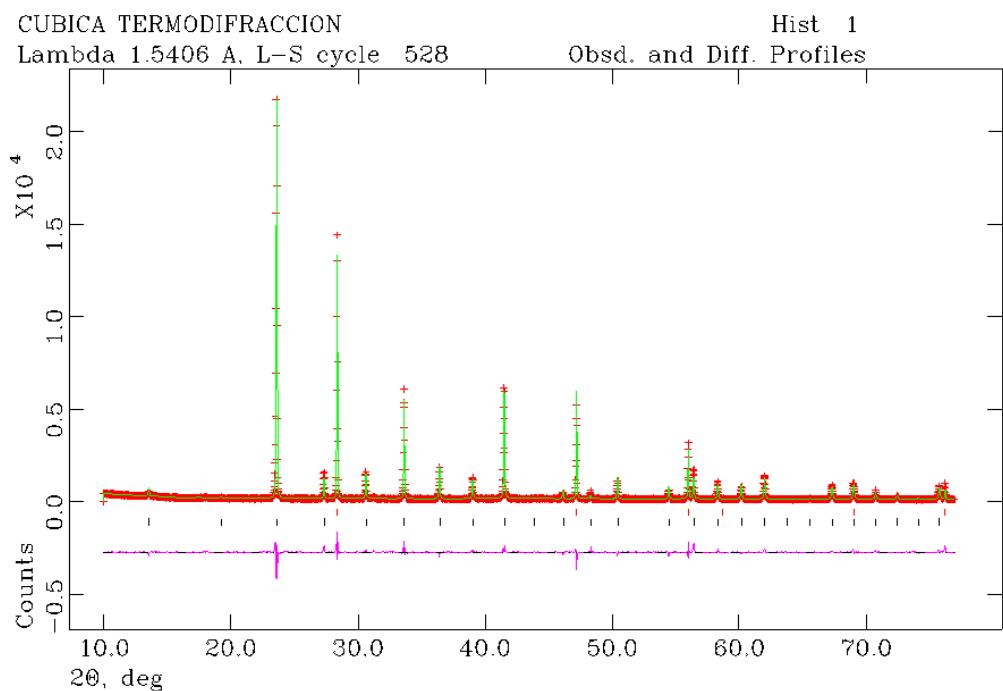


Figure S4. Laboratory X-ray powder diffraction Rietveld plot for doped ye'elimit mixed with silicon (internal standard) at 300 °C.

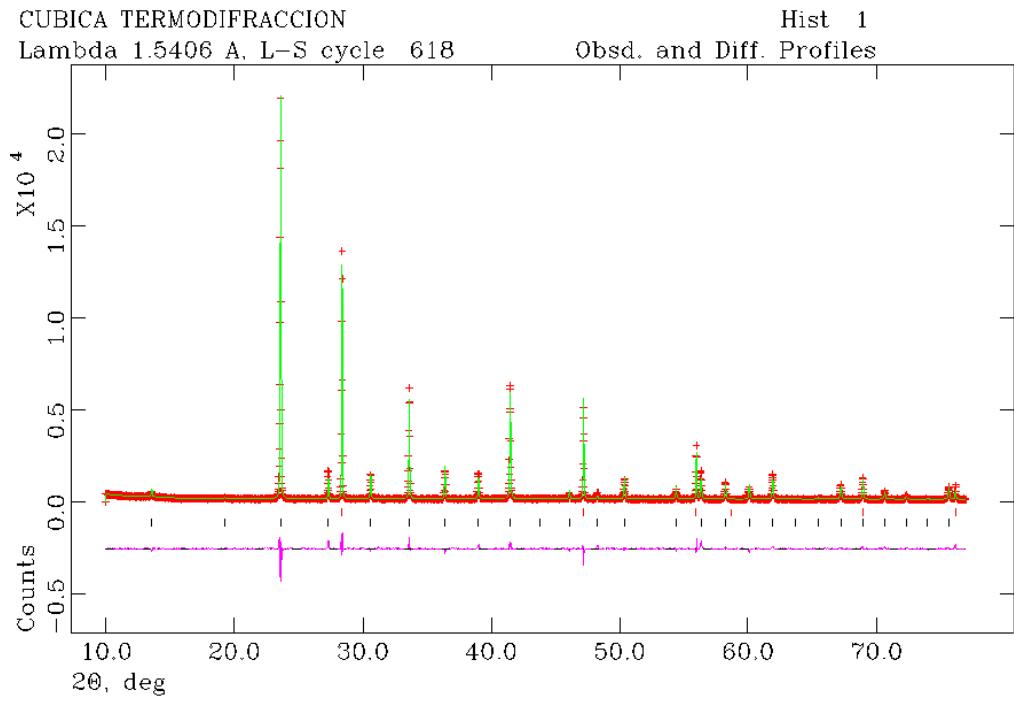


Figure S5. Laboratory X-ray powder diffraction Rietveld plot for doped ye'elimit mixed with silicon (internal standard) at 500 °C.

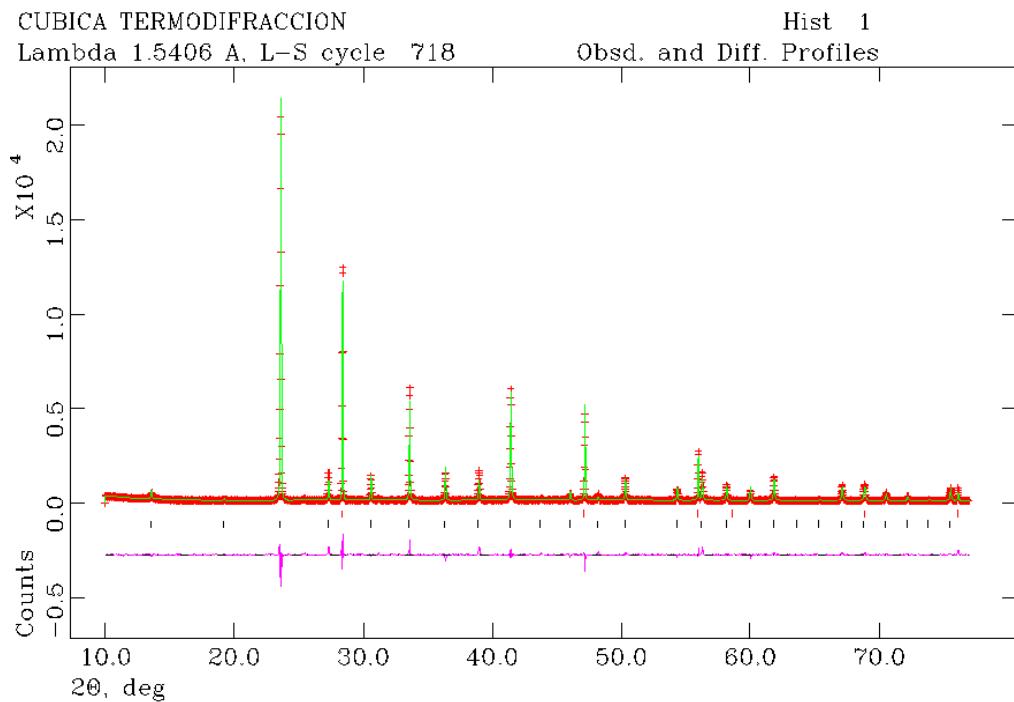


Figure S6. Laboratory X-ray powder diffraction Rietveld plot for doped ye'elimit mixed with silicon (internal standard) at 700 °C.